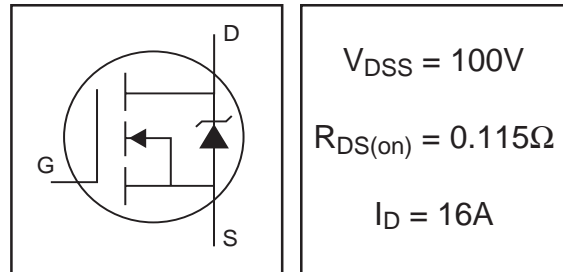


# IRFR/U3910

HEXFET® Power MOSFET

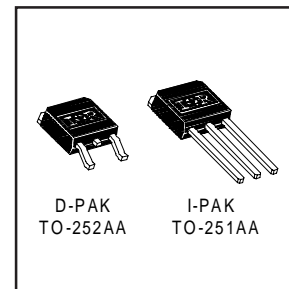
- Ultra Low On-Resistance
- Surface Mount (IRFR3910)
- Straight Lead (IRFU3910)
- Advanced Process Technology
- Fast Switching
- Fully Avalanche Rated



## Description

Fifth Generation HEXFETs from International Rectifier utilize advanced processing techniques to achieve the lowest possible on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET Power MOSFETs are well known for, provides the designer with an extremely efficient device for use in a wide variety of applications.

The D-PAK is designed for surface mounting using vapor phase, infrared, or wave soldering techniques. The straight lead version (IRFU series) is for through-hole mounting applications. Power dissipation levels up to 1.5 watts are possible in typical surface mount applications.



## Absolute Maximum Ratings

|                                 | Parameter                                       | Max.         | Units |
|---------------------------------|---|--------------|-------|
| $I_D @ T_C = 25^\circ\text{C}$  | Continuous Drain Current, $V_{GS} @ 10\text{V}$ | 16           | A     |
| $I_D @ T_C = 100^\circ\text{C}$ | Continuous Drain Current, $V_{GS} @ 10\text{V}$ | 12           |       |
| $I_{DM}$                        | Pulsed Drain Current ①⑥                         | 60           |       |
| $P_D @ T_C = 25^\circ\text{C}$  | Power Dissipation                               | 79           | W     |
|                                 | Linear Derating Factor                          | 0.53         | W/°C  |
| $V_{GS}$                        | Gate-to-Source Voltage                          | $\pm 20$     | V     |
| $E_{AS}$                        | Single Pulse Avalanche Energy②⑥                 | 150          | mJ    |
| $I_{AR}$                        | Avalanche Current①⑥                             | 9.0          | A     |
| $E_{AR}$                        | Repetitive Avalanche Energy①⑥                   | 7.9          | mJ    |
| dv/dt                           | Peak Diode Recovery dv/dt ③                     | 5.0          | V/ns  |
| $T_J$                           | Operating Junction and                          | -55 to + 175 | °C    |
| $T_{STG}$                       | Storage Temperature Range                       |              |       |
|                                 | Soldering Temperature, for 10 seconds           |              |       |

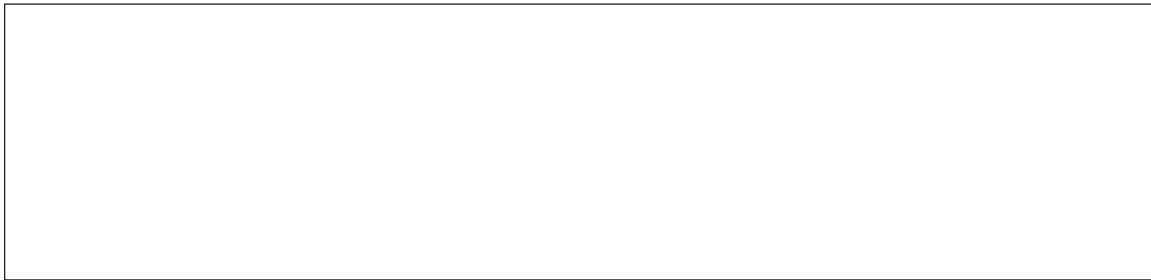
## Thermal Resistance

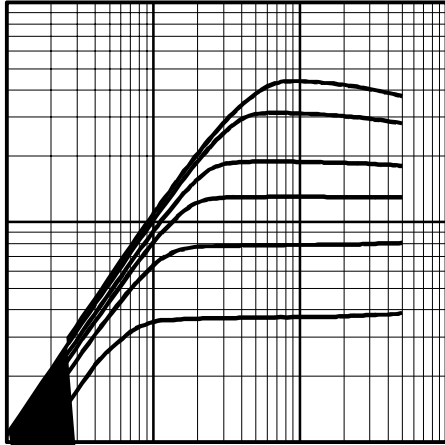
|                 | Parameter                          | Typ. | Max. | Units |
|-----------------|------------------------------------|------|------|-------|
| $R_{\theta JC}$ | Junction-to-Case                   | —    | 1.9  | °C/W  |
| $R_{\theta JA}$ | Junction-to-Ambient (PCB mount) ** | —    | 50   |       |
| $R_{\theta JA}$ | Junction-to-Ambient                | —    | 110  |       |

# IRFR/U3910

International  
**IR** Rectifier

|   | Parameter | Min. | Typ. | Max. | Units | Conditions |
|---|-----------|------|------|------|-------|------------|
| V |           |      |      |      |       |            |





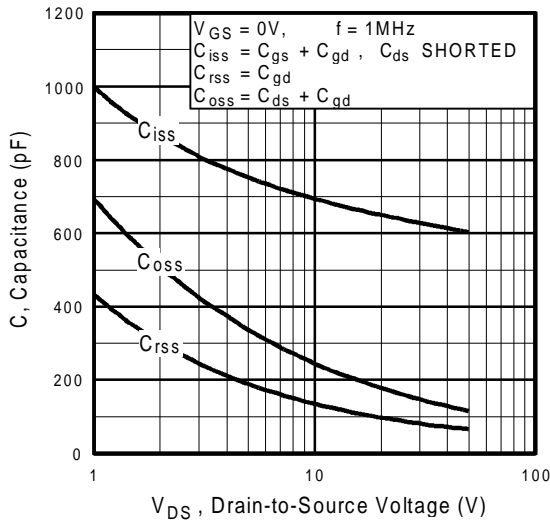
**Fig 1.** Typical Output Characteristics

**Fig 2.** Typical Output Characteristics

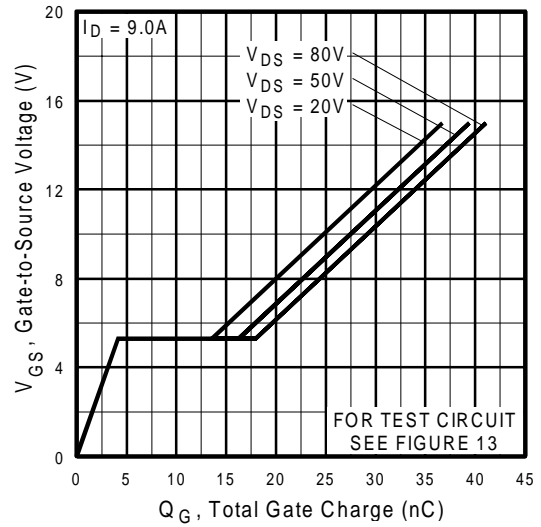
**Fig 3.** Typical Transfer Characteristics

**Fig 4.** Normalized On-Resistance  
Vs. Temperature

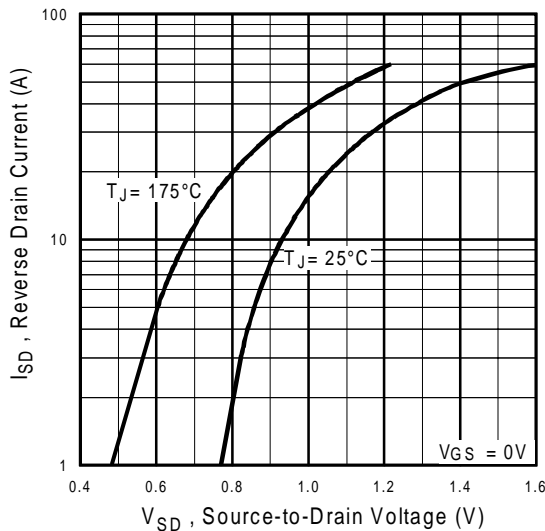
and1



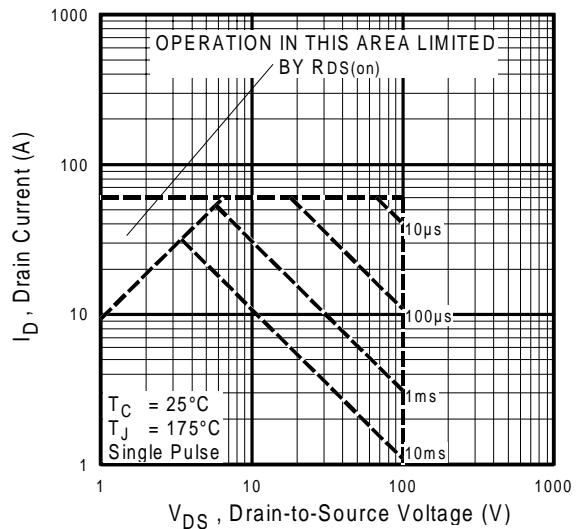
**Fig 5.** Typical Capacitance Vs. Drain-to-Source Voltage



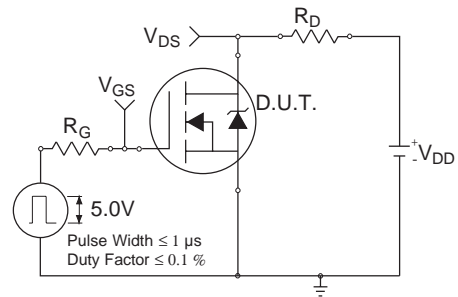
**Fig 6.** Typical Gate Charge Vs. Gate-to-Source Voltage



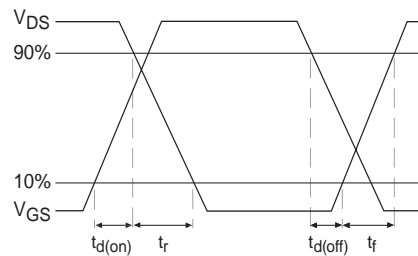
**Fig 7.** Typical Source-Drain Diode Forward Voltage



**Fig 8.** Maximum Safe Operating Area

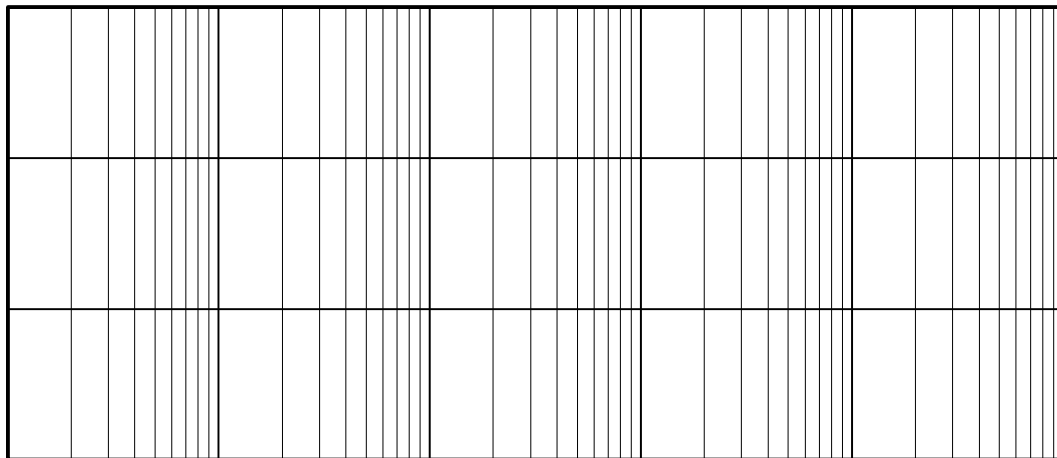


**Fig 10a.** Switching Time Test Circuit



**Fig 10b.** Switching Time Waveforms

**Fig 9.** Maximum Drain Current Vs. Case Temperature



**Fig 11.** Maximum Effective Transient Thermal Impedance, Junction-to-Case

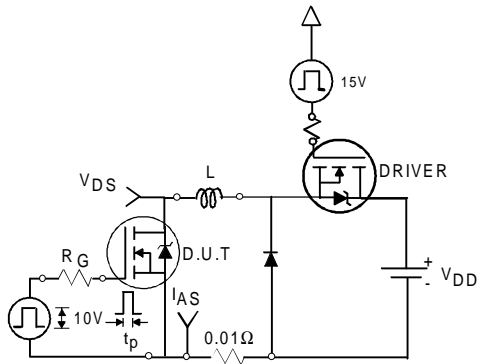


Fig 12a. Unclamped Inductive Test Circuit

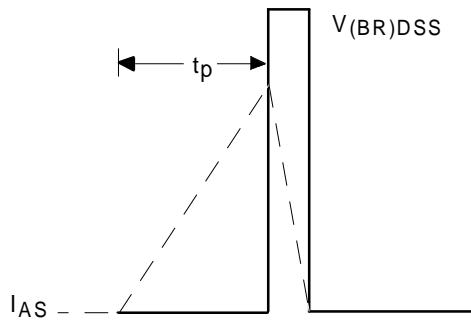


Fig 12b. Unclamped Inductive Waveforms

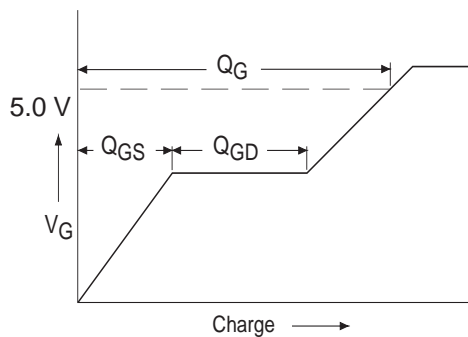


Fig 13a. Basic Gate Charge Waveform

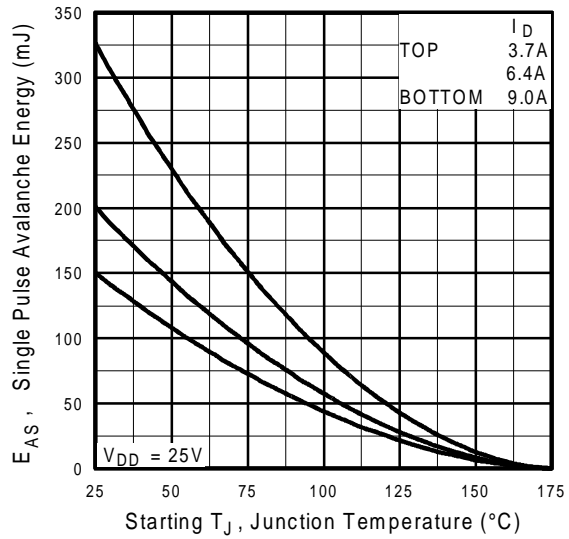


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

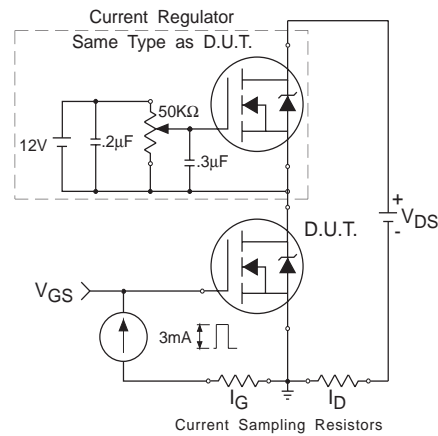
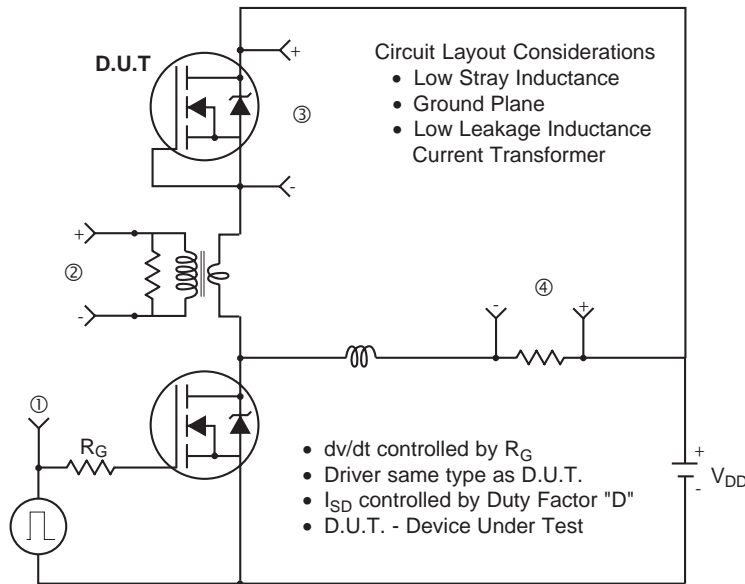


Fig 13b. Gate Charge Test Circuit

### Peak Diode Recovery dv/dt Test Circuit



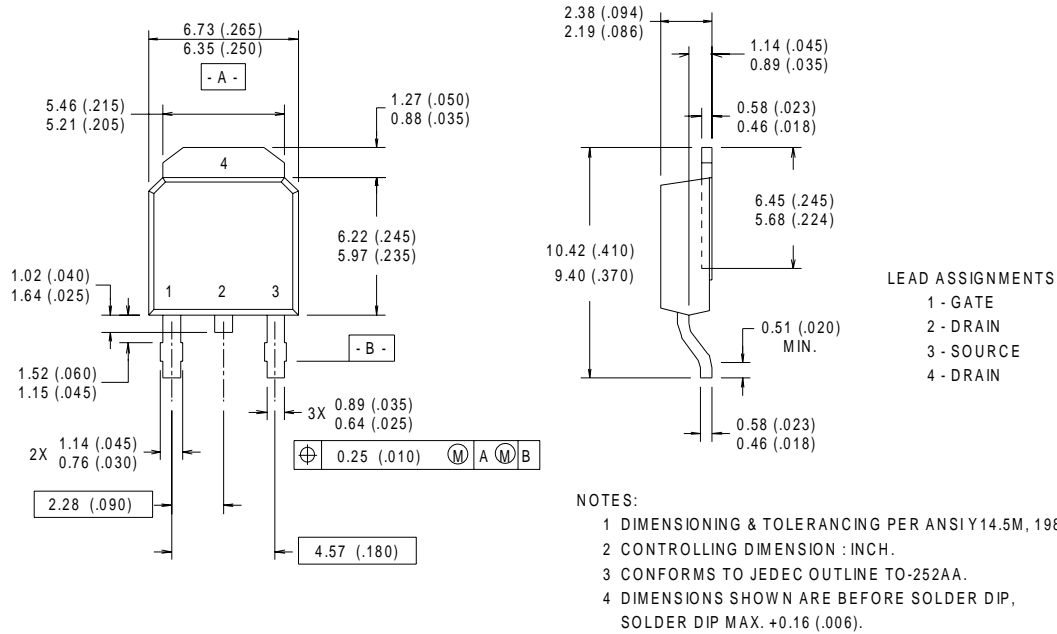
\*  $V_{GS} = 5V$  for Logic Level Devices

**Fig 14.** For N-Channel HEXFETS

**Package Outline**

**TO-252AA Outline**

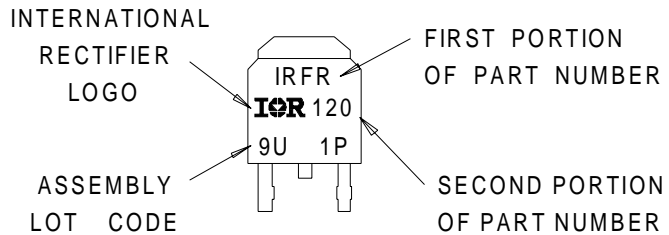
Dimensions are shown in millimeters (inches)



**Part Marking Information**

**TO-252AA (D-PARK)**

EXAMPLE : THIS IS AN IRFR120  
 WITH ASSEMBLY  
 LOT CODE 9U1P

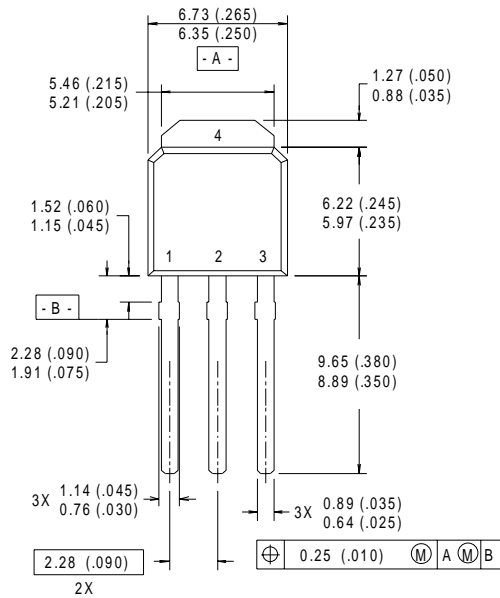




## Package Outline

### TO-251AA Outline

Dimensions are shown in millimeters (inches)



#### LEAD ASSIGNMENTS

- 1 - GATE
- 2 - DRAIN
- 3 - SOURCE
- 4 - DRAIN

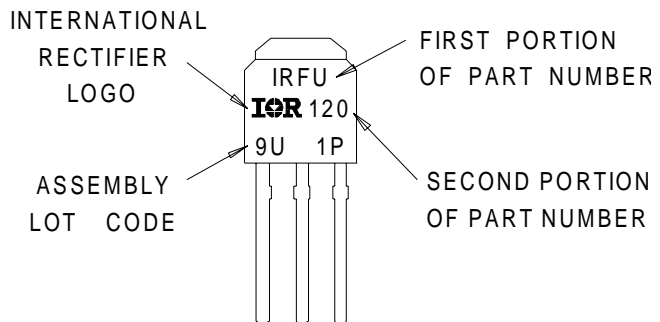
#### NOTES:

- 1 DIMENSIONING & TOLERANCING PER ANSII Y14.5M, 1982.
- 2 CONTROLLING DIMENSION : INCH.
- 3 CONFORMS TO JEDEC OUTLINE TO-252AA.
- 4 DIMENSIONS SHOWN ARE BEFORE SOLDER DIP, SOLDER DIP MAX. +0.16 (.006).

## Part Marking Information

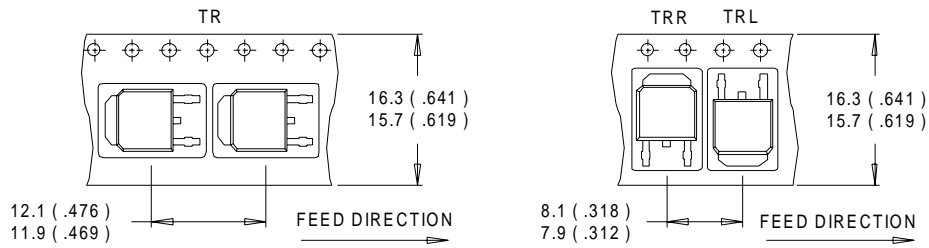
### TO-251AA (I-PARK)

EXAMPLE : THIS IS AN IRFU120  
 WITH ASSEMBLY  
 LOT CODE 9U1P

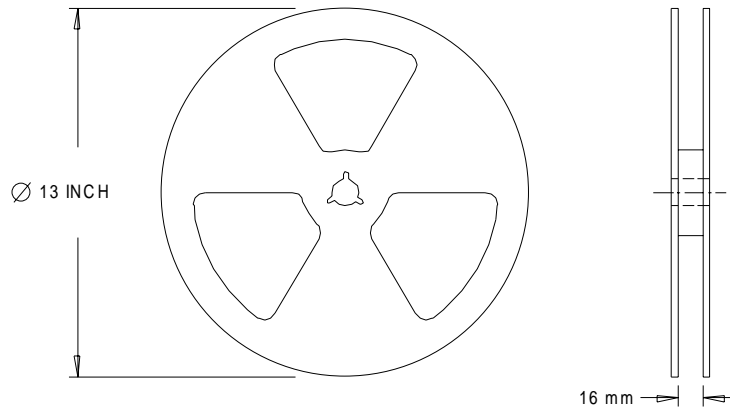


**Tape & Reel Information**

**TO-252AA**



- NOTES :
1. CONTROLLING DIMENSION : MILLIMETER.
  2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS ( INCHES ).
  3. OUTLINE CONFORMS TO EIA-481 & EIA-541.



- NOTES :
1. OUTLINE CONFORMS TO EIA-481.